


<b>Search Notes</b>  	<b>Application/Control No.</b>  10549376	<b>Applicant(s)/Patent Under Reexamination</b>  FENN, DAVID
	<b>Examiner</b>  Louis K Huynh	<b>Art Unit</b>  3721

SEARCHED			
Class	Subclass	Date	Examiner
53	329.3, 372.6, 374.8, 375.6, 477, 485, 486, 487, 289, 290	7/11/2007	LH
Updated	All above	1/16/2008	LH
Updated	All above	8/15/2008	LH
Updated	All above	3/5/2009	LH

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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